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Prepared from Pro-1390 Transmittal Letter to the United Sec d PCT/PTO 15 APR 20 Designated/Elected Office (DO/EO/US)				
Customer No.		026418		
Attorney's Docket No.:		JG-SU-5213/500577.20067		
U.S. Application No.:		10/531434		
International Application No.:		PCT.JP2003/013320		
International Filing Date:		OCTOBER 17, 2003	17 OCTOBER 2003	
Priority Date Claimed:		OCTOBER 18, 2002	18 OCTOBER 2002	
Title of Invention:		METHOD FOR MEASURING POINT DEFECT DISTRIBUTION OF SILICON SINGLE CRYSTAL INGOT		
Applicant(s) for (DO/EO/US):		Kazunari KURITA and Jun FURUKAWA		
informat	tion: This is a <b>FIRST</b> sub This is a <b>SECOND</b> (	to the United States Designated/Elected Office mission of items concerning a filing under 35 to or SUBSEQUENT submission of items concer st to begin national examination procedures [3	J.S.C. 371. ning a filing under 35 U.S.C. 371.	
[] 4. [X] 5.	include items (5), (6 The US has been el A copy of <b>Publicatio</b> 371(c)(2)] a) [X] is a b) [] has	), (9), and (21) indicated below. lected (Article 31). lected (Article 31). lected (No. WO 2004/035879 29APR04 the International hereto (required only if not communicated by the international Bure	ational Application as filed [35 U.S.C. ated by the International Bureau). au.	
`	United States Receiving Office (RO/US) 6879 29APR04 of the International Application 4(d)(4).  PCT Article 19 [35 U.S.C. 371(c)(3)] cated by the International Bureau).			
[] 9. [] 10.	c) [] have d) [] have An English language An EXECUTED Oat	e been communicated by the international Bure not been made; however, the time limit for me not been made and will not be made translation of the amendments to the claims of or declaration of the inventor(s) [35 U.S.C. 3 translation of the annexes to the International 371(c)(5)]	under PCT Article 19 [35 U.S.C. 371(c)(3)]	
Items 1	1. to 20. Below con	cern other document(s) or information incl	uded:	
[] 12. [X] 13. [] 14. [X] 15. [] 16. [] 17. [] 18. [] 19. [X] 20.	An Assignment document 3.31 is included A preliminary amer An Application Data A substitute specific A change of power of A computer-readable 1.825.  A second copy of the A second copy of the (other items or inform PCT/IB/301 19NOV)		prinary amendment) with PCT Rule 13ter.2 and 37 V+CFR1.821- is U.S.C. 154 (d)(4). conal Application under 35 U.S.C. 154 (d)(4). con Japanese and English languages,	

EXPRESS MAIL No.: EV 302 916 022 US Deposited: April 15, 2005
I hereby certify that this correspondence is being deposited with the United States Postal Service Express mail under 37 CFR 1.10 on/the date/indicated above and is addressed to: Mail Stop PCT, Commissioner For Patents, P.O. Box 1450/Alexandria, VA 22313 1450

/Ruth Montalvo Date: April 15, 2005

JC12 Rec'd Pc U.S. Application No. (if known, see 37 C.F.R. 1.50): International Application No.: PCT/JP2003/013320 Attorney's Docket No: JG-SU-[X] 21. The following fees are submitted: Applicant use Office use only **BASIC NATIONAL FEE** [X] a) 300.00 \$ 300.00 200.00 \$ 200.00 [X]b)Examination fee \$ [X] C) Search fee \$ 500.00 \$ 500.00 **TOTAL OF ABOVE CALCULATIONS: \$1,000.00** \$1,000.00 [] Additional fee for specification and drawings filed in paper over 100 sheets (excluding sequence listing or computer program listing filed in an electronic medium). The fee is \$250.00 for each additional 50 sheets of paper or fraction thereof. Total sheets Number of each additional 50 or fraction Extra sheets Rate thereof (round up to a whole number. - 100 = /50 = X \$250.00 \$ Surcharge of \$ 130.00 for furnishing the oath or declaration later than 30 month from the earliest claimed priority date (37 CFR 1.492(e)) \$ Number Filed Claims **Number Extra** Rate Total Claims: 14 - 20 X \$ 50.00 \$ Independent 3 - 3 X \$ 200.00 \$ Claims: MULTIPLE DEPENDENT CLAIM(S) (if applicable) + \$ 360.00 **TOTAL OF ABOVE CALCULATIONS:** \$1,000.00 Surcharge of \$130.00 for furnishing the oath or declaration later than [] 20 [] 30 months from the earliest claimed priority date [37 CFR 1.492(e)] **TOTAL OF ABOVE CALCULATIONS:** \$1,000.00 Applicant claims Small Entity Status [See 37 CFR 1.27] Reduction by 1/2 for filing by small entity SUBTOTAL: \$1,000.00 Processing fee of \$130.00 for furnishing the English Translation later than [] 20 [] 30 months from the earliest claimed priority date [37 CFR 1.492(f)] TOTAL NATIONAL FEE: \$1,000.00 Fee for recording the enclosed assignment [37 CFR 1.21(h)] The assignment must be accompanied by an appropriate cover sheet (PTO-1595) [37 CFR 3.28, 3.31], \$40.00 per property TOTAL FEE(S): \$1,000.00 **AMOUNT TO BE REFUNDED** \$ AMOUNT TO BE CHARGED \$ (Please note the filing fee is based on the claims in the Preliminary Amendment) a) [X] Check in the amount of \$ 1,000.00 to cover the above fees is enclosed. b)[] Please charge my Deposit Account No 50-1529 in the amount of \$ .00 to cover the fee.. c) [X] The Commissioner is hereby authorized to charge any additional fees required with this submission or to credit overpayment to Deposit Account No: 50-1529.) any Fee are to be charged to a credit card. WARNING: Information on this form may become public. Credit card information d) [] should not be included on this form. Provide credit card information and authorization on PTO-2038. NOTE: Where an appropriate time limit under 36 CFR 1.494 or 1.495 has not been met, a petition to revive [37 CFR 1.137(a) or (b)] must be filed and granted to restore the application to pending status. SEND ALL CORRESPONDENCE TO: Signature: Jules E. Goldberg, Esq. Reed Smith LLP (Customer No. 026418) Attorney: 599 Lexington Avenue Reg. No. 24,408 New York, NY 10022-7650 Date: April 15, 2005

10/531434 JC12 Rec'd PCT/PTO 1 5 APR 2005

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IN TH	E UNITED STATES PATENT AN	ID TRADEMARK OFFICE
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## VERIFIED ENGLISH TRANSLATION

OF

PUBLICATION NO.

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## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re International Application of

Kazunari KURITA et al.

International Application Number: PCT/ JP03/13310

International Filing date: October 17, 2003

For: METHOD FOR MEASURING POINT DEFECT DISTRIBUTION OF SILICON

SINGLE CRYSTAL INGOT

## **VERIFICARTION OF TRANSLATION**

Honorable Commissioner of Patents and Trademarks Washington, D.C. 20231

Sir:

I, Masayoshi Suda residing at Suda Patent Office, Nissei Higashi-Ikebukuro Bldg., Higashi-Ikebukuro 1-chome, Toshima-ku, Tokyo Japan, declare:

- (1) that I know well both the Japanese and English languages;
- (2) that I translated the above-identified International Application from Japanese into English;
- (3) that the attached English translation is a true and correct translation of the aboveidentified International Application to the best of my knowledge and belief; and
- (4) that all statements made of my knowledge are true and that all statements made on information and belief are believed to be true, and further that these statements are made with the knowledge that willful false statements and the like are punishable by fine or imprisonment, or both, under 18 UC 1001 and that such false statements may jeopardize the validity of the application or any patent issuing thereon.

March 28, 2005

Date

Masayoshi Suda